INVESTIGATION OF PHOSPHATE BASED ELECTROLYTES FOR USE DURING Cu-ECMP

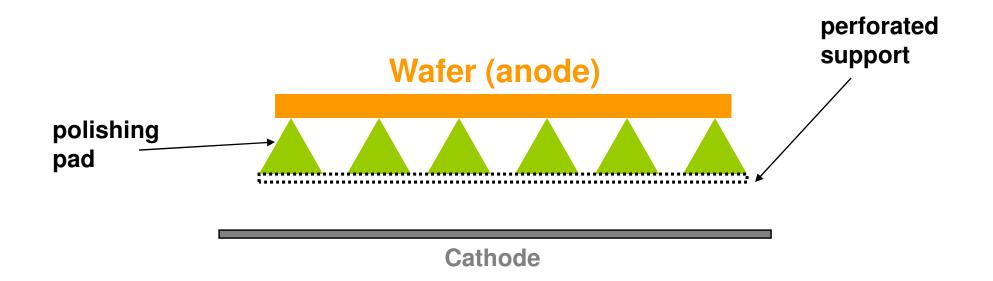
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What is ECMP?



- Potentially eliminates need for particles in slurry
- Reduce/eliminate use of strong oxidizers
 - electrons supplied by external circuit oxidize Cu

Recent Objectives

Current Studies Focus on:

- Studying ECMP using:
 - $KPO_3 H_3PO_4 / BTA$ electrolyte
 - ECMP tool to determine:
 - Removal rates
 - Planarization capabilities
- Using microfluidics to study BTA adsorption/desorption

Experimental Parameters

- pH
 - Range 0 10
- BTA Concentration
 - Range 0- 0.01 M
- Mass Transfer

Characterization

- Electrochemical Impedance Spectroscopy (EIS)
- Linear Sweep Voltametry (LSV)
- Cyclic Voltametry (CV)
- Profilometry

EHS Impact/ Metrics

- Environmental Health and Safety (EHS) impact of Electrochemical Planarization Technologies
 - Eliminating need for abrasive particles in electrolyte
 - Particles make waste difficult to treat
 - Possibly eliminating the use of strong oxidizing agents in electrolytes
 - Electrolytes without these oxidizing are less toxic and easier to treat
 - Potential reduction in electrolyte volume
 - Reduce waste generation

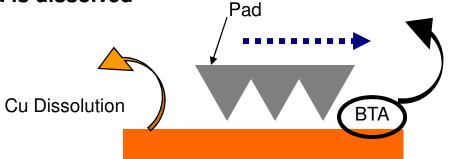
Proposed eCMP Mechanism Utilizing BTA

- **1. BTA adheres to surface**
 - Forms BTA-Cu complex

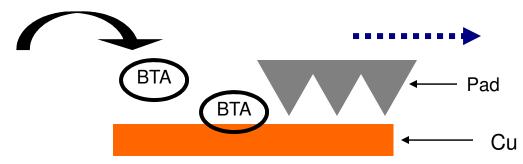


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- 2. Pad mechanically removes Protective BTA layer
 - Exposed Cu is dissolved



3. BTA re-attaches to protect new CU surface



Results of BTA Inhibitor Study

pH 0



No BTA

0.001 M BTA

0.005 M BTA

0.01 M BTA

pH 2

0.25

0.20

0.15

0.10

0.05

0.00

0.0

0.5

A/cm²

- Scan rate 5 mV/s RT 100 RPM
 - **pH 0** BTA shows no passivation effect
 - pH 2 Even at lowest concentration (0.001 M), BTA demonstrates significant passivation
 - pH 7 BTA has little effect compared to base solution due to the nature of oxide formation at high pH's

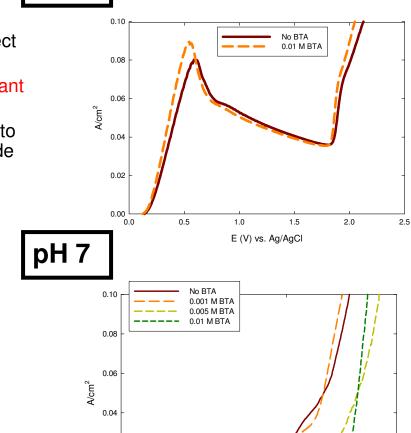
1.5

1.0

E (V) vs. Ag/AgCl

2.0

2.5



SRC/Sematech Engineering Research Center for Environmentally Benign Semiconductor Manufacturing

0.02

0.00 -

0.5

1.0

E (V) vs/ Ag/AgCl

1.5

2.0

6

2.5

pH 2 Optimization

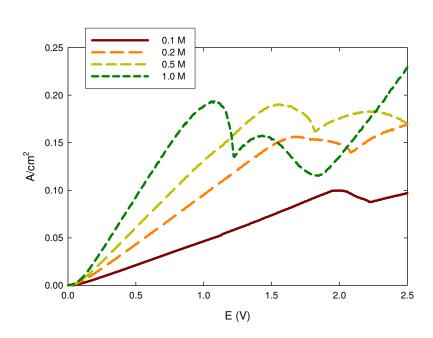
•Electrolyte molarity is important when considering IR drop

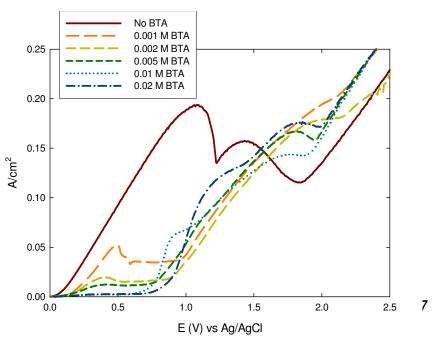
- •Above 1 M, no change in polarization curve
- •1 M chosen as appropriate molarity for electrolyte
- •Various BTA concentrations of 1 M pH 2

•Good operating voltage between 0.5 - 1.0 V, before BTA loses passivation effect



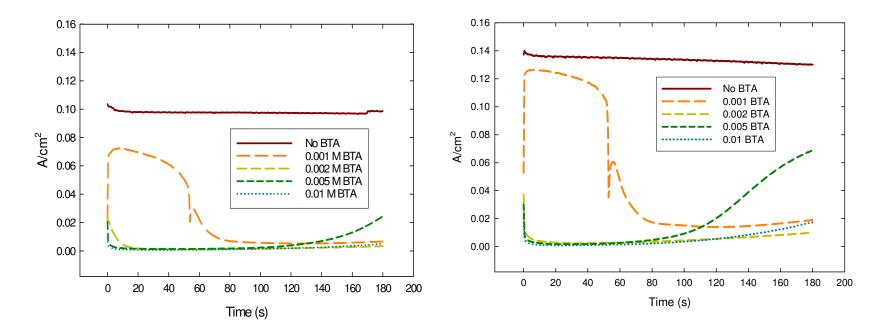
pH 2 with different BTA concentrations: 0.001 M to 0.02 M





Chronoamperometry

Gives insight into BTA film stability over time scales appropriate for ECMP
Applied voltages are vs. Ag/AgCl reference performed on RDE



0.5 V for 180s

0.7 V for 180s

Chronoamperometry

•High applied voltages

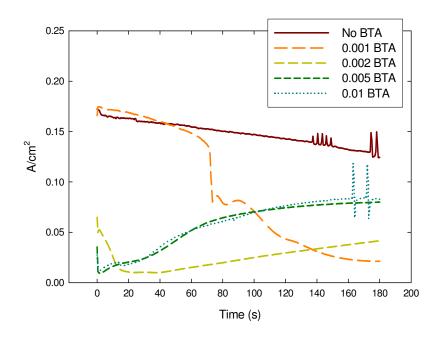
•base solution is not stable

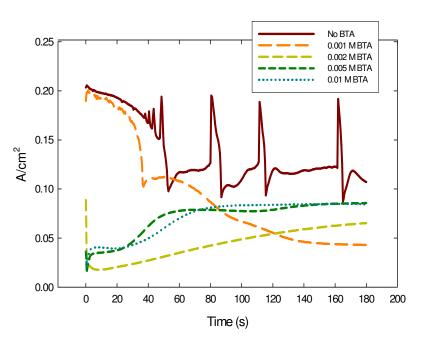
•BTA has less passivation effect

•Applied voltages are vs. Ag/AgCl reference performed on RDE



1.0 V for 180s



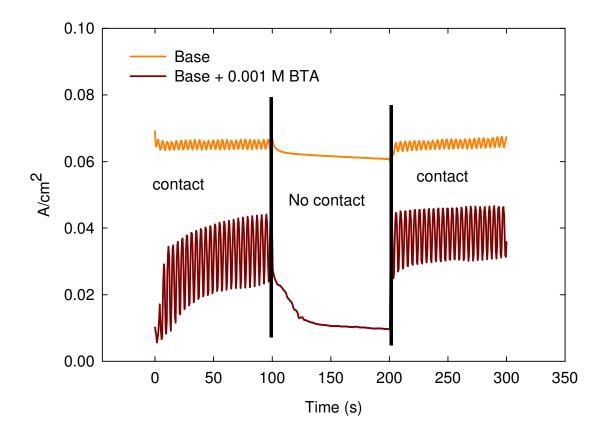


Contact vs. No Contact

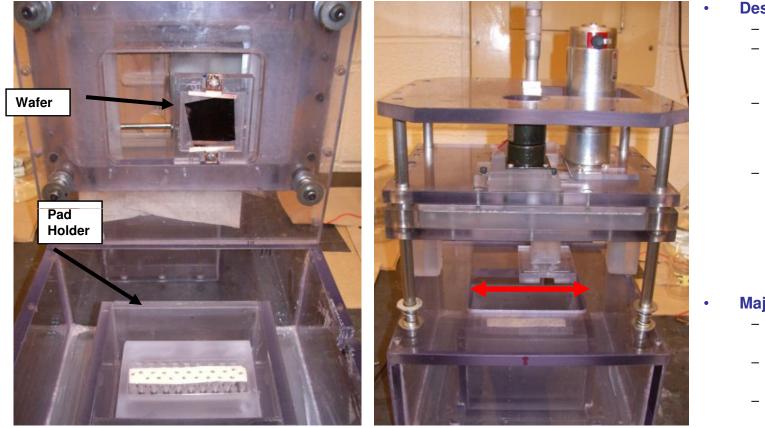
- Using RDE setup with pad
 - 0.5 V vs Ag/AgCl

•Current density decreases as BTA passivation increases when contact is stopped

•Little to no change in current density when No BTA is present



ECMP Tool



Design features:

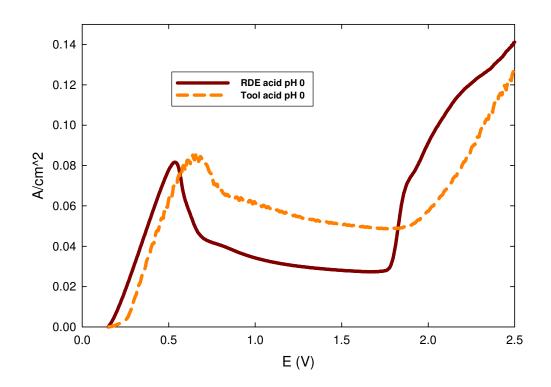
- 2D linear motion
- Apply and control low downforces (<1 PSI)
- Ease of changing between various electrolytes and pads
- Operate in contact and non-contact modes

Major Characterization

- Metal-removal rates
- Selectivity
- Planarization efficiency

ECMP Tool

Good Agreement with RDE polarization curves

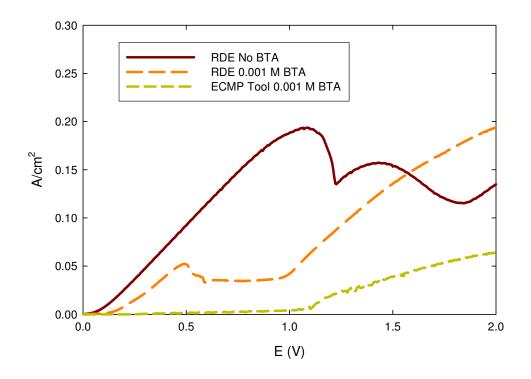


Anodic polarization curves of H₃PO₄ using e-CMP tool and RDE

ECMP Tool

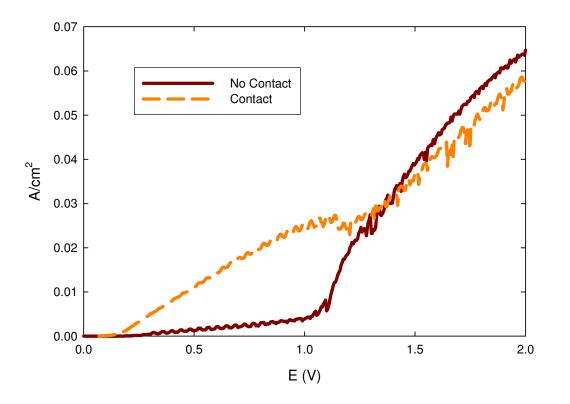
•Polarization curves from RDE and ECMP Tool – pH 2

- 0.001 M BTA both instruments
- RDE No BTA



Polishing Results

- pH 2 0.001 M BTA \rightarrow Pad Contact vs. No Pad Contact
 - Suba[™] 500 Pad



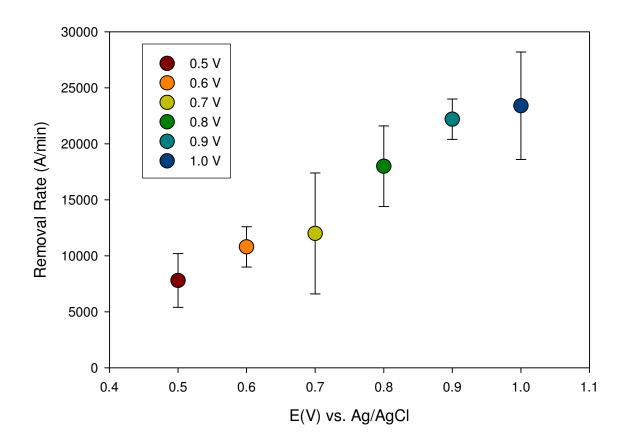
Removal Rates

•1M pH 2, data from various experiments including:

- w/ out BTA, w & w/out contact
- w/ 0.001 M BTA with contact

•Removal rate calculated by weight loss

Downforce ~1 psi

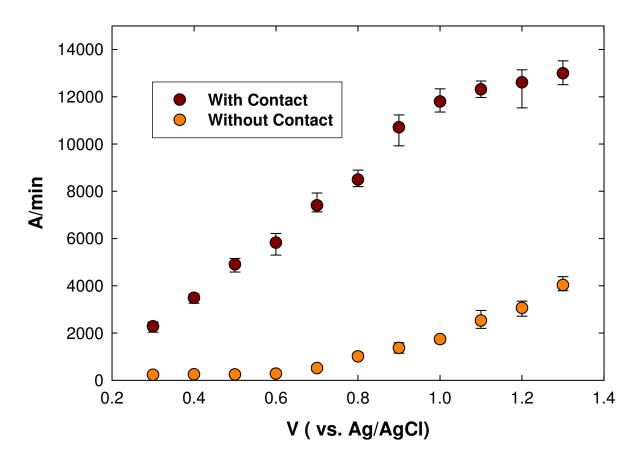


Removal Rates

•1M pH 2, 0.01 M BTA *

•With and without contact

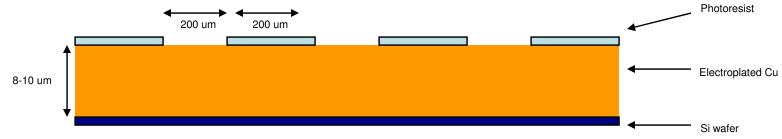
•Downforce: 0.5 psi



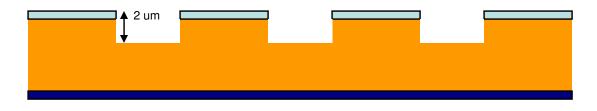
[•]Data aquired from research group in Tawain - TSMC

ECMP Test Structure

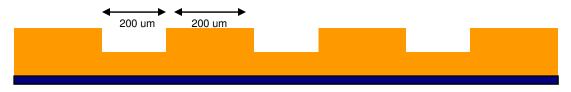
Step 1: Starting with a thick Cu layer (~8-10 um), a photoresist (SU-8) was spin coated (5-10 nm) and then lithography is used to pattern a structure with line spacing ~200 um



Step 2: After the pattern is made with SU-8, it is then electropolished in phosphoric acid operating in the limiting current range (~1.5 V vs. ref) for 200s for 2 um trenches (500s for 2.5-3 um trenches)



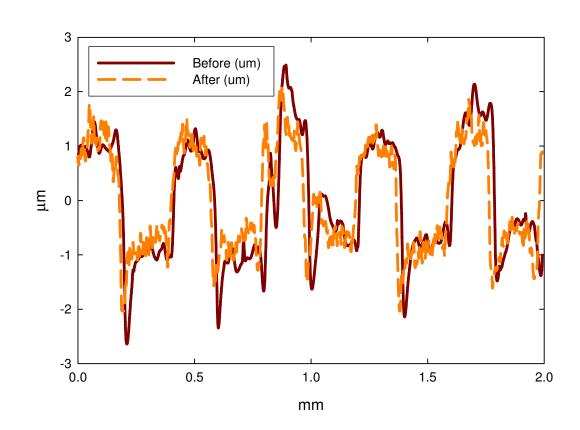
Step 3: To remove the photoresist, SU-8 developer was used. Exposure time was ~10s. Because the developer increased surface roughness, another electropolishing treatment is used post developer, to yield the final test structure. Trench heights can vary by using different electropolishing regimes.



ECMP Planarization

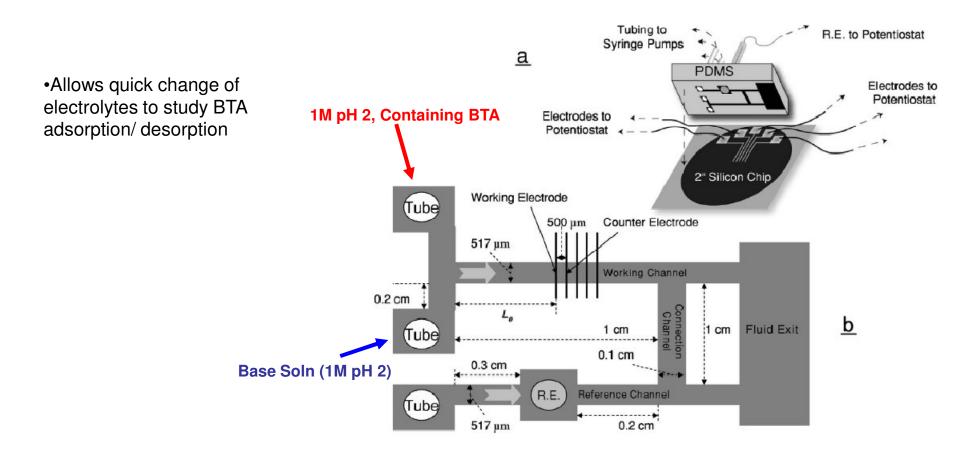
- Control experiment showing NO planarization
- 1 M pH 2, No BTA, No Contact
- Treatment:
 - 0.5 V vs. Ag/AgCl
 - 300 s
 - No BTA

Currently working towards planarization capabilities with pad contact when BTA is present



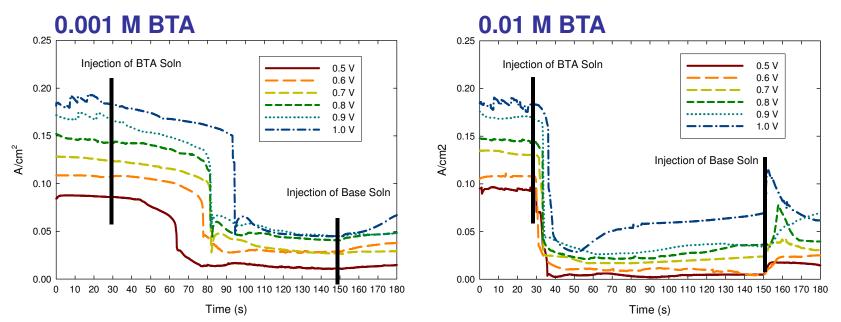
Microfluidics

Microfluidic Device Setup¹



Microfluidics

- •BTA adsorption in phosphate based electrolyte
- •0 30 sec, Base Solution (1M pH 2),
- •30 150 sec, BTA electrolyte (1M pH 2, 0.001 & 0.01 M BTA)
- •150 180 sec, Base Solution (1M pH 2)

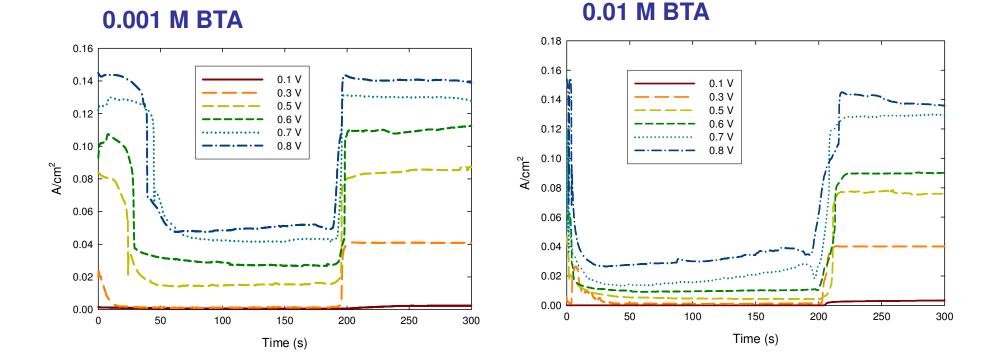


Microfluidics

•BTA desorption in phosphate based electrolyte

•0 – 180 sec, BTA electrolyte (1M pH 2, 0.001 & 0.01 M BTA)

•180 – 300 sec, Base Solution (1M pH 2)



Summary

<u>Microfluidic Experiments</u>

- Device working
- Showing unique results concerning BTA adsorption/desorption
 - Important for inhibitor optimization to reduce appearance of microscratches on Cu surface
 - Important for cleaning

ECMP Experiments

- Device accuracy confirmed with RDE experiments
- Removal rates established for operation window of applied potential (0.5 V to 1.0 V)
 - Above 1.0 V BTA loses passivation ability
- Test structure build for characterizing planarization
 - Initial patterned structure testing has commenced

Future Work

- Finish up investigation of phosphate based electrolyte using ECMP tool
 - Acquire solid planarization data
- Begin investigation on polishing liner materials
 - Ru
- <u>Acknowledgments</u>
 - Alan West
 - Jeng-Yu Lin
 - Columbia University
 - SRC/Sematech
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 - TSMC